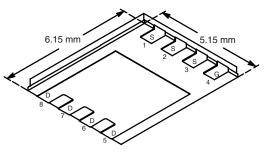


Vishay Siliconix

N-Channel 25-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	$\mathbf{R}_{DS(on)}$ (Ω) \mathbf{I}_{D} (A) ^a \mathbf{Q}_{g} (1)				
25	0.0063 at V _{GS} = 10 V	50 ^a	9.3 nC			
	0.008 at V _{GS} = 4.5 V	50 ^a	9.5 110			



PowerPAK[®] SO-8

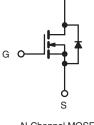
Bottom View

FEATURES

- Halogen-free According to IEC 61249-2-21 . Definition
- TrenchFET[®] Power MOSFET
- 100 % R_g Tested •
- 100 % UIS Tested •
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

- Server
- POL
- DC/DC High Side



Ordering Information: SiR408DP-T1-GE3 (Lead (Pb)-free and Halogen-free)

N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	25	v	
Gate-Source Voltage		V _{GS}	± 20	V	
Continuous Drain Current (T _J = 150 °C)	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$ $T_{A} = 70 °C$	I _D	50 ^a 50 ^a 21.5 ^{b, c} 17.2 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	70		
Avalanche Current	L = 0.1 mH	I _{AS}	35		
Avalanche Energy	L = 0.1 mm	E _{AS}	61	mJ	
Continuous Source-Drain Diode Current $T_{C} = 25 \text{ °C}$ $T_{A} = 25 \text{ °C}$		۱ _S —	37.2 4 ^{b, c}	A	
Maximum Power Dissipation	$T_{C} = 25 °C$ $T_{C} = 70 °C$ $T_{A} = 25 °C$ $T_{A} = 70 °C$	P _D	44.6 28.6 4.8 ^{b, c} 3.1 ^{b, c}	W	
Operating Junction and Storage Temperature Range Soldering Recommendations (Peak Temperature) ^{d, e}		T _J , T _{stg}	- 55 to 150 260	°C	

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical Maximum		Unit		
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	21	26 °C/W			
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	2.4	2.8	0/11		

Notes:

a. Based on $T_C = 25$ °C. Package limited. b. Surface Mounted on 1" x 1" FR4 board.

e. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

f. Maximum under Steady State conditions is 70 °C/W.

COMPLIANT

HALOGEN FREE

c. t = 10 s.

d. See Solder Profile (www.vishay.com/ppg?73257). The PowerPAK SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

SiR408DP

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$	25			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L _ 250 uA		27		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 25 V, V_{GS} = 0 V$			1	- μΑ	
		V_{DS} = 25 V, V_{GS} = 0 V, T_{J} = 55 °C			5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	50			Α	
		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$		0.0052	0.0063	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 15 A		0.0064	0.008		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		85		S	
Dynamic ^b							
Input Capacitance	C _{iss}			1230			
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		315		pF	
Reverse Transfer Capacitance	C _{rss}			115			
		V _{DS} = 12.5 V, V _{GS} = 10 V, I _D = 20 A		21.5	33		
Total Gate Charge	Qg			9.3	14	nC	
Gate-Source Charge	Q _{gs}	V_{DS} = 12.5 V, V_{GS} = 4.5 V, I_{D} = 20 A		3.2			
Gate-Drain Charge	Q _{gd}			2.6			
Gate Resistance	R _g	f = 1 MHz		0.8	1.6	Ω	
Turn-On Delay Time	t _{d(on)}			20	30		
Rise Time	t _r	V_{DD} = 12.5 V, R_{L} = 12.5 Ω		28	42	- ns	
Turn-Off Delay Time	t _{d(off)}	$\text{I}_{\text{D}}\cong$ 1.0 A, V_{GEN} = 4.5 V, R_{g} = 1 Ω		30	45		
Fall Time	t _f			11	20		
Turn-On Delay Time	t _{d(on)}			12	25		
Rise Time	t _r	V_{DD} = 12.5 V, R_{L} = 12.5 Ω		15	25		
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}\cong$ 1.0 A, V_GEN = 10 V, R_g = 1 Ω		30	45		
Fall Time	t _f			8	15		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			44.6	٨	
Pulse Diode Forward Current	I _{SM}				70	A	
Body Diode Voltage	V _{SD}	$I_{S} = 4.0 \text{ A}, V_{GS} = 0 \text{ V}$		0.75	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			26	50	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	$L = 4.0.0$ dl/dt = 100.0/ ± 0.00 T = 05.00		24	50	nC	
Reverse Recovery Fall Time	ta	$I_F = 4.0 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		16.5		ns	
Reverse Recovery Rise Time	t _b			9.5			

Notes:

a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

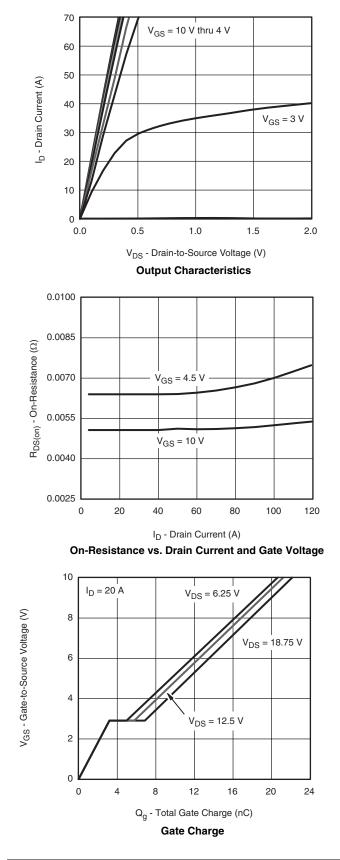
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

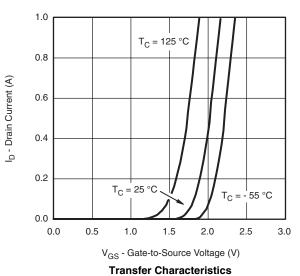


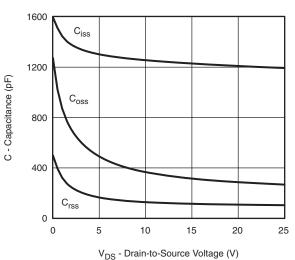
SiR408DP

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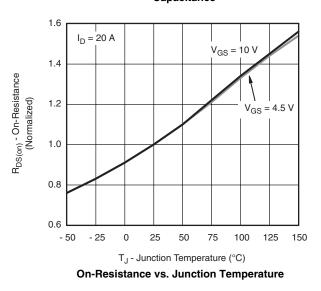
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted







Capacitance



Document Number: 65036 S09-1396-Rev. A, 20-Jul-09

SiR408DP

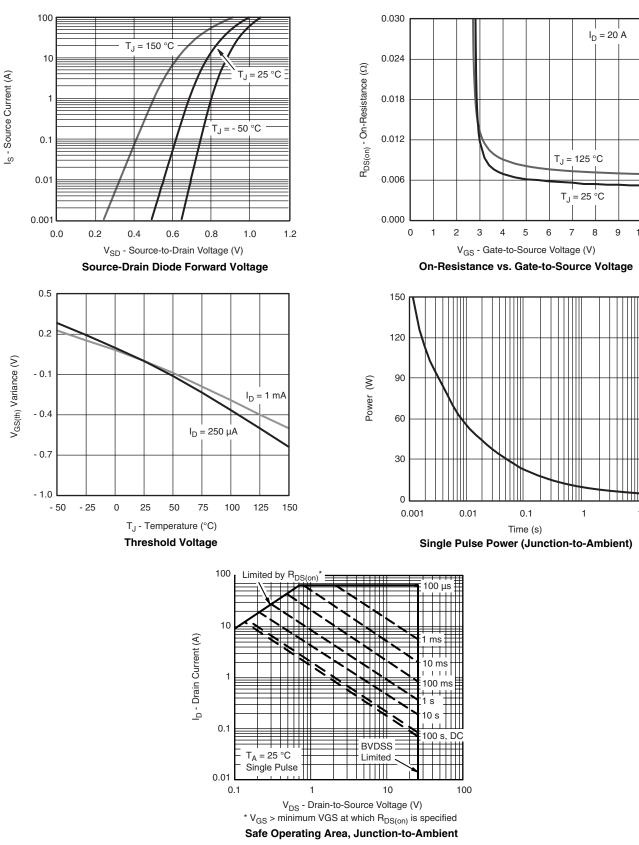
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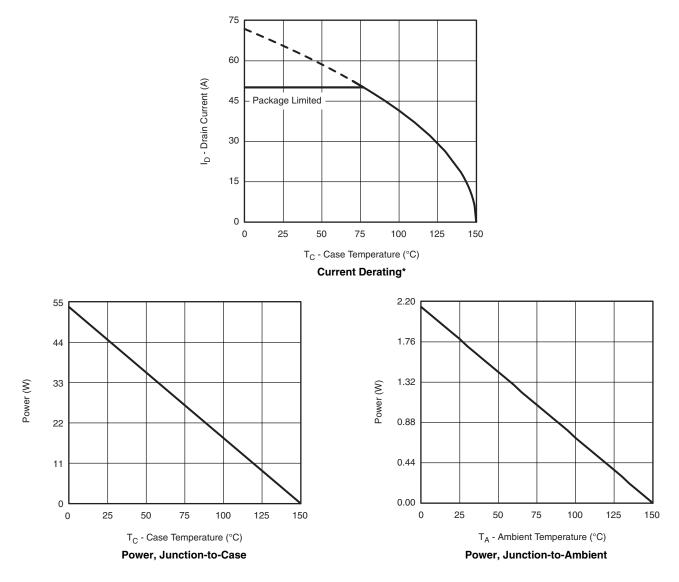
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SiR408DP Vishay Siliconix

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

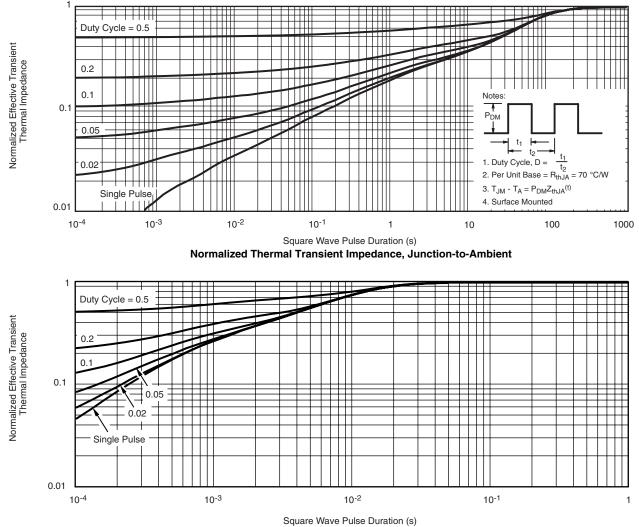


* The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Case

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see www.vishay.com/ppg?65036.



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